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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZX585-C47-Q Part Description									
							Nexperia DHAM	Zener			
							SMD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects					
			TEST								
			Pre- and Post-Stress								
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below					
		JESD22-A113									
		Bake Tamb = 125 °C	24 hours								
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours								
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0					
		MIL-STD-750-1									
	HTRB	M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse									
# B1	Bias	voltage	1000 hours	250	11400	0					
# DI	Dias	MIL-STD-750-1	1000 110015	230	11400	0					
		MIL-STD-750-1 M1038 Method B									
	SSOP	$T_j = T_j max$, $I_z = 100\%$ of max. datasheet									
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0					
	тс	JESD22-A104									
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0					
	UHAST	JESD22-A118									
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	—96 hours	311	14080	0					
		JESD22-A102									
	AC	Tamb = 121 °C, RH = 100 %									
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)									
	H3TRB	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of									
# AD -1	High Humidity High Temperature Reverse Bias		1000 hours	311	14080	0					
# A2 alt	remperature Reverse Dias		1000 nours	211	14080	U					
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔT_j =									
# A5	Intermittent Operating Life	, , , ,	1000 hours	312	14120	0					
" ""	internitione operating Life		1000 110015	512	11120	•					
	RSH	JESD22-A111									
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0					
	SD										
# C10	Solderability	J-STD-002		19	6660	0					
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[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

2,68E+09
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